

Notice of References Cited

Application/Control No.

10/574,219

Applicant(s)/Patent Under
Reexamination
SCHULZ ET AL.

Examiner

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Art Unit

1616

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U.S. PATENT DOCUMENTS

*		Document Number	Date	Name	Classification
		Country Code-Number-Kind Code	MM-YYYY		
*	A	US-7,294,330 B2	11-2007	Banowski et al.	424/65
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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		Country Code-Number-Kind Code	MM-YYYY			
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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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